

L Number	Hits	Search Text	DB	Time stamp
-	33	SEM and objective adj lens and beam and secondary adj electron and auger	USPAT; EPO; JPO; DERWENT	2003/10/17 14:36
-	26	((SEM and objective adj lens and beam and secondary adj electron and auger) and analys6	USPAT; EPO; JPO; DERWENT	2003/10/17 13:55
-	10	((SEM and objective adj lens and beam and secondary adj electron and auger) and analys6) and shield	USPAT; EPO; JPO; DERWENT	2003/10/17 11:34
-	20	((SEM and objective adj lens and beam and secondary adj electron and auger) and analys6) and resolution	USPAT; EPO; JPO; DERWENT	2003/10/17 14:00
-	9	((SEM and objective adj lens and beam and secondary adj electron and auger) and analys6) and magnetic adj field	USPAT; EPO; JPO; DERWENT	2003/10/17 14:00
-	1	(SEM and objective adj lens and beam and secondary adj electron and auger) and capacitor same image	USPAT; EPO; JPO; DERWENT	2003/10/17 14:36
-	38	SFM and objective adj lens and beam and auger	USPAT; EPO; JPO; DERWENT	2003/10/17 14:36
-	1	(SEM and objective adj lens and beam and auger) and capacitor same image	USPAT; EPO; JPO; DERWENT	2003/10/17 14:58
-	1	(SEM and objective adj lens and beam and auger) and electrostatic adj capacitor	USPAT; EPO; JPO; DERWENT	2003/10/17 14:59
-	18	(SEM and objective adj lens and beam and auger) and electrostatic	USPAT; EPO; JPO; DERWENT	2003/10/17 14:59